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## Infrared and Thermoelectric Properties of Bi<sub>x</sub>Te<sub>v</sub>-Based Alloyed Thin Films

Tomoya Ino1 and Shigeo Yamaguchi1,2,\*

<sup>1</sup>Department of Electrical, Electronic and Information Engineering, Kanagawa University
3-27-1 Rokkakubashi, Kanagawa-ku, Yokohama 221-8686, Japan

<sup>2</sup>High-Tech Research Center, Kanagawa University
3-27-1 Rokkakubashi, Kanagawa-ku, Yokohama 221-8686, Japan

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We studied the infrared (IR) and thermoelectric properties of ( $\rm Bi_x Te_y + Cd$ ) and ( $\rm Bi_x Te_y + InSb$ ) alloyed thin films prepared on  $\rm SiO_2$  glass substrates by electron beam evaporation (EB). Cd was used in terms of the enhancement of sensitivity to IR radiation because CdTe is known to be highly sensitive to IR radiation. The voltage sensitivities were 0.71 and 43.9 mV for  $\rm Bi_2 Te_{2.4}$  and  $\rm Bi_2 Cd_{2.6} Te_{5.5}$ , respectively, at a bias current of 10 mA and a blackbody furnace temperature of 1000°C. The maximum values of the power factor ( $P_{\rm f}$ ) were  $1.15\times10^{-3}$  W/mK² at 450 K for  $\rm Bi_2 Te_{2.4}$ ,  $2.46\times10^{-4}$  W/mK² at 550 K for  $\rm Bi_2 Te_{3.6}+InSb_6$ , and  $8.90\times10^{-6}$  W/mK² at 550 K for  $\rm InSb_{2.2}$ .

\*Corresponding author: e-mail: yamags18@kanagawa-u.ac.jp